Docket No.

240306US2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Fumihiko SANO

SERIAL NO: New Application

GAU:

FILED:

Herewith

EXAMINER:

FOR:

SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE AND METHOD OF MANUFACTURING THE SAME

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

Marvin J. Spivak

Registration No. 24,913

C. Irvin McClelland Registration Number 21,124

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FOR: SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE AND METHOD OF

MANUFACTURING THE SAME

STATEMENT OF RELEVANCY

Reference AO (8-274258) on Form PTO-1449:

Making some conductive trenches under the electrical-PAD, and behaving as "bypass-condenser" between Power and Ground.

Reference AP (2001-102529) on Form PTO-1449:

Capacitor Device constructed with MIM (Metal-Insulator-Metal) in the Semiconductor integrated circuit.

Form PTO 1449		U.S. DEPARTMEN		ATTY DOCKET NO.		SERIAL NO.		
(Modified) PATENT AND TRADEMARK OFFICE			240306US2		New Application			
				APPLICANT				
LIST OF	REFE	RENCES CITED BY A	PPLICANT	Fumihiko SANO				
				FILING DATE		GROUP		
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATI YES		
	AO	8-274258	10/18/96	Japan (with English Abstract)			Х	
	ΑP	2001-102529	04/13/01	Japan (with English Abstract)			Х	
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		OTHER R	REFERENCES (Including Author, Title, Date, Pertiner	nt Pages, e	tc.)		
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